

Electronics Manufacturing

Subpart I, Greenhouse Gas Reporting Program

What Must Be Monitored for Manufacturers of Electronics Devices?

Measure or estimate these parameters annually

	Annual manufacturing capacity of each fab (m ²).		Inventory of each fluorinated GHG and N ₂ O stored in containers at the end of the reporting year.
	Annual production in terms of substrate surface area (m ²) for each fab, including specification of the substrate.		Acquisitions of each fluorinated GHG and N ₂ O through purchase records or other transactions (kg).
	Amount of each fluorinated GHG consumed in process sub-types, and process types; and the amount of N ₂ O consumed in CVD and other N ₂ O-using processes (kg).		Disbursements of each fluorinated GHG and N ₂ O.
	Annual fab-level emissions of each fluorinated GHG, including each input gas and each by-product gas, used for the plasma etching/wafer cleaning process type and each of the process sub-types associated with the chamber cleaning process type, including in-situ plasma chamber clean, remote plasma chamber clean, and in-situ thermal chamber clean (metric tons).		Disbursements under exceptional circumstances of gases through sales or other transactions.
			Number of containers of gas returned by the facility to gas distributors.
			Full capacities of gas containers used.
	Annual emissions of N ₂ O for each N ₂ O-using process type, on a fab basis (metric tons).		Fab-wide heel factors for each gas and container type used.
	Inventory of each fluorinated GHG and N_2O stored in containers at the beginning of the reporting year.		Process sub-type-specific, and process type-specific fluorinated GHG apportioning factors; and CVD-specific and other N ₂ O-using process-specific N ₂ O apportioning factors.
Electronics Manufacturing Monitoring Checklist Greenhouse Gas Reporting Program			40 CFR 98, subpart I February 2018

If you elect to use the stack test method:

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	For each stack system in the fab for which testing is required, measure the emissions of each fluorinated GHG from the stack system by conducting an emission test. In addition, measure the fab-specific consumption of each fluorinated GHG by the tools that are vented to the stack systems tested.		Develop fab-specific emission factors for each fluorinated GHG input gas consumed and each fluorinated GHG formed as a by- product; and calculate fab-level fluorinated GHG emissions.			
			Total annual emissions of fluorinated GHGs from all of the combined stack systems that are not tested in the fab.			
If you use fluorinated heat transfer fluids (HTFs):						
	Annual emissions of fluorinated HTFs on a fab basis using the mass balance approach, as applicable.		Acquisitions of each fluorinated HTF, including the amounts purchased from chemical suppliers, equipment suppliers with or inside equipment, and returned to the facility after off-site recycling.			
	The density of each fluorinated HTF used at the facility.		Total nameplate capacity of equipment that uses a fluorinated HTF and is newly installed during the reporting year.			
	Inventory of each fluorinated HTF in containers, other than equipment, at the beginning of the reporting year.		Total nameplate capacity of equipment that uses a fluorinated HTF and is removed from service during the reporting year.			
	Inventory of each fluorinated HTF in containers, other than equipment, at the end of the reporting year.		Disbursements of each fluorinated HTF, including amounts returned to chemical suppliers, sold with or inside of equipment, and sent off-site for verifiable recycling or destruction.			

If controlled emissions from the use of abatement systems are reported:

The total time, in minutes, that Fraction of each fluorinated GHG abatement system p, connected to used in process sub-types, or process process tool(s) in the fab using types with abatements systems; and input gas in process sub-type or the fraction of N₂O used in CVD or process type j, is not in operational other N₂O-using processes. mode. Properly measured and class average DREs, when the EPA default DRE factor is not used. Fraction of each fluorinated GHG destroyed or removed in abatement Uptime of each abatement system systems for process sub-types, or used at the facility connected to process types; Fraction of N2O used process tools in the fab. in each N₂O-using process with abatement systems; and the fraction The total time each abatement of N₂O destroyed or removed in system is in operational mode and abatement systems for CVD or other fluorinated GHGs or N₂O are N₂O-using processes. flowing through the connected process tools. Amount of each fluorinated GHG consumed for process sub-type, and The total time fluorinated GHGs or process type fed into each abatement N₂O are flowing through process device used at the facility; the amount tools connected to each abatement of N₂O consumed for CVD and other system. N₂O-using processes fed into each abatement system used at the facility.

For more information, see the information sheet for Electronics Manufacturing at: <u>https://www.epa.gov/ghgreporting/subpart-i-information-sheet</u>.

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